Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/774,308	VIEIRA ET AL.
Examiner	Art Unit
Hanh Phan	2613

	SEAR	CHED	
Class	Subclass	Date	Examiner
398	175	09/12/06	M
	176		
	152		
	65		
	79		
359	326	09/12/06	HIP
	332,3	30	
	344,3	31	•
	333		-
385	1,2	09/12/06	np
	4,5		
	15		
replate	teard	09/12/06	W

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
398	175,176	09/12/06	HP	
	152,65			
359	326,332	09/12/06	пр	
-	330,331 333,341			
385	1,2,4,5	- 09/12/06	HI	
	15			

SEARCH NOT (INCLUDING SEARCH		
	DATE	EXMR
East heard see	09/12/06	H
in the ple.		
i'ee reard.		
joo reard.		
PGPUB Lext reard	09/12/01	AP
tee interference		
teard printont.		
·		
		